





an Open Access Journal by MDPI

# Fault-Tolerant Digital Circuits: Protection Techniques, CAD Tools and Emerging Applications

Guest Editor:

#### Prof. Dr. Juan Antonio Maestro

ARIES Research Center, Universidad Nebrija, 28040 Madrid, Spain

Deadline for manuscript submissions:

closed (31 March 2021)

## **Message from the Guest Editor**

Reliability is a growing concern for electronic digital circuits. In this Special Issue, we are interested in exploring new protection techniques for electronic systems, CAD tools to perform reliability tests and novel applications, in different fields, which can benefit from the use of fault-tolerant circuits.

These topics include but not limited to:

- New protection techniques for digital circuits
- Fault-tolerant computer architectures
- Error correction codes (ECC) to increase reliability in innovative ways
- Signal and image processing systems with a focus on reliability
- CAD tools and methods to emulate error injection test processes
- Novel applications of fault tolerant digital circuits

Welcome to contribute.











an Open Access Journal by MDPI

## **Editor-in-Chief**

#### Prof. Dr. Flavio Canavero

Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

# **Message from the Editor-in-Chief**

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

### **Author Benefits**

**Open Access:** free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science),

CAPlus / SciFinder, Inspec, and other databases.

Journal Rank: JCR - Q2(Electrical and Electronic Engineering) CiteScore - Q2 (Electrical

and Electronic Engineering

#### **Contact Us**